TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7MZ273FK

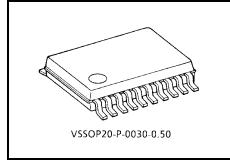
Low-Voltage Octal D-Type Flip-Flop with Clear with 5-V Tolerant Inputs and Outputs

The TC7MZ273FK is a high-performance CMOS octal D-type flip-flop. Designed for use in 3.3-V systems, it achieves high-speed operation while maintaining CMOS low power dissipation.

The device is designed for low-voltage (3.3-V) applications, but can also be used to interface both inputs and outputs with a 5-V supply environment.

D-input signal is sent to Q-output when clock rises. Clear input is Low-active and all flip-flop outputs are reset Low.

All inputs are equipped with protection circuits to guard against static discharge.



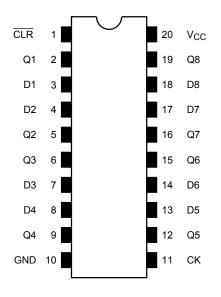
Weight: 0.03 g (typ.)

Features

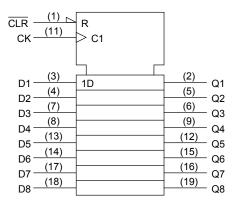
- Low voltage operation: V_{CC} = 2.0 V~3.6 V
- High-speed operation: $t_{pd} = 8.5 \text{ ns (max)} (V_{CC} = 3.0 \text{ V} \sim 3.6 \text{ V})$
- Output current: $|I_{OH}|/I_{OL} = 24 \text{ mA (min) (V}_{CC} = 3.0 \text{ V)}$
- Latch-up performance: -500 mA
- Package: VSSOP (US20)
- Power-down protection is provided for all inputs and outputs.
- Pin and function compatible with the 74 Series (74AC/VHC/HC/F/ALS/LS etc.) 273 type.

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Pin Assignment (top view)



IEC Logic Symbol

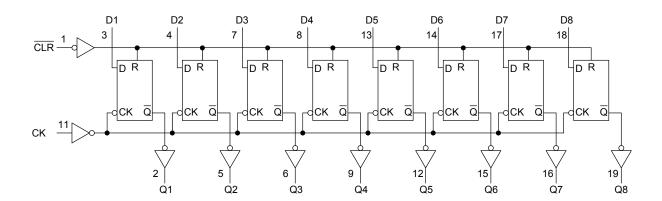


Truth Table

	Inputs		Outputs	Function
CLR	D	CK	Q	Tunction
L	Х	Х	L	Clear
Н	L		L	
Н	Н		Н	_
Н	Х	\neg	Qn	No change

X: Don't care

System Diagram



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Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit	
Supply voltage range	V _{CC}	-0.5~7.0	V	
DC input voltage	V _{IN}	-0.5~7.0	V	
DC output voltage	Vout	−0.5~7.0 (Note 2)	V	
DC dulput voltage	VOU1	-0.5~V _{CC} + 0.5 (Note 3)	V	
Input diode current	I _{IK}	-50	mA	
Output diode current	lok	±50 (Note 4)	mA	
DC output current	lout	±50	mA	
Power dissipation	P_{D}	180	mW	
DC V _{CC} /ground current	I _{CC} /I _{GND}	±100	mA	
Storage temperature	T _{stg}	-65~150	°C	

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in off-state

Note 3: High or low state. I_{OUT} absolute maximum rating must be observed.

Note 4: Vout < GND, Vout > Vcc

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit	
Supply voltage	V _{CC}	2.0~3.6	V	
Supply voltage	vcc vcc	−1.5~3.6 (Note 2)	V	
Input voltage	V _{IN}	0~5.5	V	
Output voltage	V _{OUT}	0~5.5 (Note 3)	٧	
Output voltage		0~V _{CC} (Note 4)		
Output current	I _{OH} /I _{OI}	±24 (Note 5)	mA	
Output current	iOH/iOL	±12 (Note 6)	ША	
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dv	0~10 (Note 7)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: Output in off state

Note 4: High or low state

Note 5: $V_{CC} = 3.0 \sim 3.6 \text{ V}$

Note 6: $V_{CC} = 2.7 \sim 3.0 \text{ V}$

Note 7: $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$



Electrical Characteristics

DC Characteristics ($Ta = -40 \sim 85$ °C)

Charac	eteristics	Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit
lament valtage	High level	V _{IH}		_ :		2.0	_	V
Input voltage	Low level	V _{IL}		_	2.7~3.6		0.8	V
				I _{OH} = -100 μA	2.7~3.6	V _{CC} - 0.2	_	V
	High level	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OH} = -12 mA	2.7	2.2	_	
				I _{OH} = -18 mA	3.0	2.4	_	
Output voltage				I _{OH} = -24 mA	3.0	2.2	_	
				I _{OL} = 100 μA	2.7~3.6		0.2	
Low	Low level Voi	V _{OL}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OL} = 12 mA	2.7	_	0.4	
	Low level	w level VOL	lo	I _{OL} = 16 mA	3.0		0.4	
				I _{OL} = 24 mA	3.0	_	0.55	
Input leakage cur	rent	I _{IN}	V _{IN} = 0~5.5 V		2.7~3.6	_	±5.0	μΑ
Power off leakage	e current	I _{OFF}	$V_{IN}/V_{OUT} = 5.5 \text{ V}$		0	_	10.0	μΑ
Quiescent supply current	Icc	V _{IN} = V _{CC} or GND		2.7~3.6		10.0		
		V _{IN} = 3.6~5.5 V		2.7~3.6		±10.0	μΑ	
Increase in I _{CC} per input		Δlcc	$V_{IN} = V_{CC} - 0.6 V$		2.7~3.6	_	500	

AC Characteristics ($Ta = -40 \sim 85$ °C)

Characteristics	Symbol	Test Condition		Min	Max	Unit
Characteristics	Symbol	rest condition	V _{CC} (V)	IVIIII		
Maximum clock frequency	f _{MAX}	Figure 1, Figure 2	2.7	_	_	MHz
Maximum Glock frequency		rigure 1, rigure 2	3.3 ± 0.3	150	_	
Propagation delay time (CK-Q)	t _{PLH}	Figure 4 Figure 0	2.7		9.5	- ns
Propagation delay time (CR-Q)	t _{PHL}	Figure 1, Figure 2	3.3 ± 0.3	1.5	8.5	
Propagation delay time (CLR -Q)	tou	Figure 1, Figure 3	2.7		9.5	- ns
Propagation delay time (CLK -Q)	t _{PHL}	Figure 1, Figure 3	3.3 ± 0.3	1.5	8.5	
Minimum pulse width (CK)	t _{w (H)}	Figure 1, Figure 2	2.7	3.3	_	- ns
Willimum puise width (CK)	tw (L)		3.3 ± 0.3	3.3	_	
Minimum bus width (CLR)	t _{w (L)}	Figure 3	2.7	3.3	_	ns
Willimum bus width (CLR)			3.3 ± 0.3	3.3	_	
Minimum oot un timo	4	Figure 1, Figure 2	2.7	2.5	_	ns
Minimum set-up time	ts	rigure 1, rigure 2	3.3 ± 0.3	2.5	_	
Minimum hold time	t _h	Figure 1, Figure 2	2.7	1.5	_	ns
Minimum noid time			3.3 ± 0.3	1.5	_	
Minimum removal time	t _{rem}	Figure 4	2.7	2.5	_	
		Figure 4	3.3 ± 0.3	2.0	_	ns
Output to output alcow	t _{osLH}	41.1.	2.7	_	_	no
Output to output skew	tosHL	(Note)	3.3 ± 0.3	_	1.0	ns

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Note: This parameter is guaranteed by design.

 $(t_{\text{OSLH}} = |t_{\text{pLHm}} - t_{\text{pLHn}}|, \, t_{\text{OSHL}} = |t_{\text{pHLm}} - t_{\text{pHLn}}|)$

Dynamic Switching Characteristics

(Ta = 25°C, Input: $t_r = t_f = 2.5$ ns, $C_L = 50$ pF, $R_L = 500$ Ω)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Quiet output maximum dynamic V _{OL}	V _{OLP}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V
Quiet output minimum dynamic V_{OL}	V _{OLV}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Input capacitance	C _{IN}	_	3.3	7	pF
Output capacitance	C _{OUT}	_	0	8	pF
Power dissipation capacitance	C _{PD}	f _{IN} = 10 MHz (Note	3.3	25	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$

AC Test Circuit

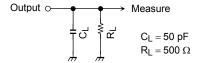


Figure 1

AC Waveform

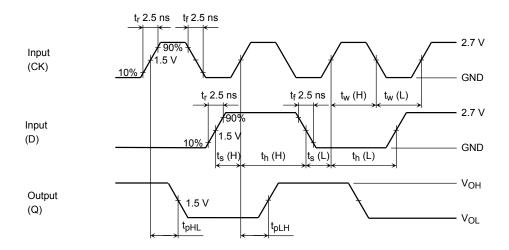


Figure 2 t_{pLH} , t_{pHL} , t_w , t_s , t_h

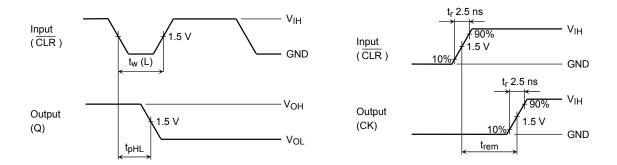
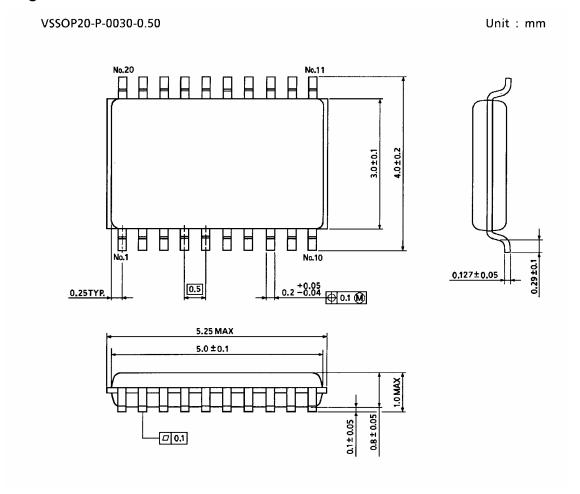


Figure 3 tpLH, tpHL

Figure 4 t_{rem}

Package Dimensions



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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